

BEST AVAILABLE COPY

SEARCHED			
Class	Sub.	Date	Exmr.
250	492.2		
	492.3		
	492.21		
	492.1		
	396 R		
260	491.1		
	491.1		
Updated		06/20/03	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
WEST	Date	Exmr.
<u>Keyword Search</u>		
FIB / ion beam (column or array) & (focus & ion beam)		
+ secondary particle detect		
+ declared & (elements or lens)		
+ tilt angle	01/23/03	
+ characters & near (angle or text or material or wafer) + (three degrees tilt angle)	01/23/03	BES
+ through-lens view	01/23/03	
Updated 06/20/03 (signal muted) (no source) (multiple sources or grating)	06/20/03	BES

INTERFERENCE SEARCHED			
Class	Sub.	Date	Exmr.